

Form PTO 1449 (Modified)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY DOCKET NO. 295210US0PCT	SERIAL NO. New US PCT Application Based on PCT/JP05/03756
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Keiji ENDO, et al.	
		FILING DATE Herewith	GROUP 10590275 - GAU: 1656

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
AA						
AB						
AG						
AD						
AE						
AE						
AG						
AH						
AI						
AJ						
AK						
AL						
AM						
AN						

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
				YES	NO
AO	2003 054179	07/03/03	WO		NO
AP	6 327472	11/29/94	JP (English abstract only)		NO
AO	2000 210081	08/02/00	JP (English abstract only)		NO
AR	2000 184882	07/04/00	JP (English abstract only and equivalent of US 2002 0197698)		NO
AS					
AT					
AU					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

AV	SCHNIDER, U. et al., "Amplification of the housekeeping sigma factor in <i>Pseudomonas fluorescens</i> CHAO enhances antibiotic production and improves biocontrol abilities", <i>J. Bacteriol.</i> , Vol.177, No.18, pgs. 5387-5392, 1995.		
AW	HELDENWANG, W. G. et al., "The sigma factors of <i>Bacillus subtilis</i> ", <i>Microbiol. Rev.</i> , Vol. 59, No. 1, pgs. 1-30, 1995.		
AX	BIRD, T. et al., "The effect of supercoiling on the in vitro transcription of the <i>spoIIA</i> operon from <i>Bacillus subtilis</i> ", <i>Biochimie</i> , Vol. 74, pgs. 627-634, 1992.		
AY	PARK, S.G. et al., "Sequencing and phylogenetic analysis of the <i>spoIIA</i> operon from diverse <i>Bacillus</i> and <i>Paenibacillus</i> species", <i>Gene</i> , Vol. 194, pgs. 25-33, 1997.		
AZ	<input type="checkbox"/> Additional References sheet(s) attached		
Examiner	/Jae W. Lee/ (02/11/2010)	Date Considered	02/11/2010

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.